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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

10/045,766

Confirmation No: 3061

Applicant

Ralph C. Tuttle, et al.

Filed

10/23/2001

TC/A.U.

2811

Examiner

Andre C. Stevenson

Docket No.

5000.142

Customer No.: For

021176 PATTERN FOR IMPROVED VISUAL INSPECTION

OF SEMICONDUCTOR DEVICES

July 22, 2005

Certificate of Corrections Branch Commissioner for Patents Post Office Box 1450 Alexandria, VA 22313-1450

Certificate JUL 2 8 2005

REQUEST FOR ISSUE OF CORRECTED PATENT

of Correction

Sir:

Pursuant to 37 CFR §1.322(b), the Assignee of U.S. Patent No. 6,903,446 requests that the U.S. Patent and Trademark Office (PTO) issue a corrected patent in lieu of and with like effect as a certificate of correction with respect to the above-referenced patent. A brief explanation is listed hereafter and on enclosed form PTO/SB/44. Tabulated supporting data is also included, with the tab numbers corresponding to the following numbered paragraphs.

- 1. May 5, 2004 Applicants file an Amendment and Reply to Office Action submitting that Claims 1, 4, 5, 10, 11, 14-17, 19, 20, and 27 are in condition for allowance.
- 2. August 25, 2004 Examiner Stevenson mails a Notice of Allowability in response to the May 5, 2004, Amendment and Reply. Claims 10 and 27 are omitted.
- 3. October 13, 2004 The undersigned practitioner telephones Examiner Stevenson regarding the omitted claims. Examiner Stevenson states that he will call back

Certificate of Corrections Branch Commissioner for Patents Page 2 Confirmation No. 3061 US Patent 6,903,446 β 2

if there is a reason the claims were not allowed. Otherwise, he will issue a Supplemental Notice of Allowability.

- 4. October 19, 2004 Examiner Stevenson issues a Supplemental Notice of Allowability including Claims 10 and 27.
 - 5. November 23, 2004 Issue Fee paid.
- 6. June 7, 2005 Patent No. 6,903,446 issues omitting the allowed subject matter claimed in Claims 10 and 27 (as amended in the May 5, 2004, Amendment and Reply to Office Action).

Accordingly, the Assignee requests that the PTO issue a corrected patent listing original and amended (per the May 5, 2004, Amendment and Reply) Claims 1, 4, 5, 10, 11, 14-17, 19, 20, and 27. Because the PTO is at fault in this matter, no fee is enclosed.

Thank you for your prompt assistance in this matter.

Respectfully submitted,

and Market

James M. Corbitt, Ph.D. Registration No. 52,768

Enclosures
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UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

PATENT NO. : 6,903,446 B2

DATED

: June 7, 2005

INVENTOR(S): Tuttle et al.

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Pursuant to 37 CFR §1.322(b), the Assignee of U.S. Patent No. 6,903,446 requests that the U.S. Patent and Trademark Office (PTO) issue a corrected patent in lieu of and with like effect as a certificate of correction with respect to the above-referenced patent. A brief explanation is listed hereafter and on enclosed form PTO/SB/44. Tabulated supporting data is also included.

- 1. May 5, 2004 Applicants file an Amendment and Reply to Office Action submitting that Claims 1, 4, 5, 10, 11, 14-17, 19, 20, and 27 are in condition for allowance.
- 2. August 25, 2004 Examiner Stevenson mails a Notice of Allowability in response to the May 5, 2004, Amendment and Reply. Claims 10 and 27 are omitted.
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Accordingly, the Assignee requests that the PTO issue a corrected patent listing original and amended (per the May 5, 2004, Amendment and Reply) Claims 1, 4, 5, 10, 11, 14-17, 19, 20, and 27. Because the PTO is at fault in this matter, no fee is enclosed.

MAILING ADDRESS OF SENDER:

PATENT NO.

6,903,446 B7_

Summa & Allan, P.A.

11610 N. Community House Road, Suite 200

Charlotte, NC 28277

No. of additional copies

This collection of information is required by 37 CFR 1.322, 1.323, and 1.324. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 1.0 hour to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Attention Certificate of Corrections Branch, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

10/045,766

Confirmation No: 3061

Applicant

Ralph C. Tuttle, et al.

Filed .

10/23/2001

TC/A.U.

2811

Examiner

Andre C. Stevenson

Docket No.

5000.142

Customer No.:

021176

For_

PATTERN FOR IMPROVED VISUAL INSPECTION

OF SEMICONDUCTOR DEVICES

July 21, 2005

SUPPORTING DATA

FOR

REQUEST FOR ISSUE OF CORRECTED PATENT

FOR

US PATENT NO. 6,903,446

Auto-Reply Facsimile Transmission



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11610 NORTH COMMUNITY HOUSE RD.
SUITE 200
BALLANTYNE CORPORATE PARK
CHARLOTTE, NC 28277

T: 704.945.6700

F: 704.945.6735

W: WWW.PSUMMA.COM

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Please find attached a Reply to Notice of Non-Compliant Amendment for filing in the above-referenced application. Thank you.

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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

10/045,766

Confirmation No: 3061

Applicants

Tuttle et al.

Art Unit: 2812

Filed

10/23/2001

Examiner: Andre C. Stevenson

Docket No.

5000.142

For

PATTERN FOR IMPROVED VISUAL INSPECTION OF

SEMICONDUCTOR DEVICES

May 5, 2004

Commissioner for Patents Post Office Box 1450 Alexandria, VA 22313-1450

REPLY TO NOTICE OF NON-COMPLIANT AMENDMENT

Sir:

This responds to the Office communication mailed April 26, 2004.

Amendments to the Claims begin on page 2 of this paper.

Remarks and arguments begin on page 10 of this paper.

Tuttle, et al. Ser. No. 10/045,766 Filed: 10/23/2001 Page 2

Amendments to the Claims:

- 1. (currently amended) A labeled semiconductor material comprising:
- a surface of a semiconductor material silicon carbide; and
- a first metal layer on portions but not all of said surface;
- said metal layer forming a pattern with rotational symmetry of C_n, where n is at least

2.

Claims 2-3 (canceled)

4. (currently amended) A labeled semiconductor according to Claim 2 A labeled semiconductor material comprising:

a surface of silicon carbide; and

a first metal layer on portions but not all of said surface;

said metal layer forming a pattern with rotational symmetry of C_n, where n is at least

<u>2:</u>

a second metal layer on portions but not all of said surface of said semiconductor material;

said second metal layer forming a pattern different from said first metal layer pattern;

said second pattern having rotational symmetry of C_n where n is at least 2; and wherein each of said first and second patterns forms an X pattern.

5. (currently amended) A-labeled semiconductor according to Claim 4 A labeled semiconductor material comprising:

a surface of silicon carbide; and

a first metal layer on portions but not all of said surface;

said metal layer forming a pattern with rotational symmetry of C_n, where n is at least

Ser. No. 10/045,766

Filed: 10/23/2001

Page 3

a second metal layer on portions but not all of said surface of said semiconductor material;

said second metal layer forming a pattern different from said first metal layer pattern; and

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said second pattern having rotational symmetry of C_n where n is at least 2;

wherein each of said first and second patterns forms an X pattern; and

wherein each X pattern further comprises a tab portion perpendicular to at least one of the arms of said X pattern.

Claims 6-9 (canceled)

- 10. (currently amended) A labeled semiconductor material according to claim 9 1 wherein said metal layer is selected from the group consisting of nickel, titanium, gold, platinum, vanadium, aluminum, alloys thereof and layered combinations thereof.
 - 11. (currently amended) A semiconductor structure comprising:
 - a substrate having at least one planar face;
- a first metal layer on said planar face, and covering some, but not all of said planar face in a first predetermined geometric pattern;

a second metal layer on said planar face, and covering some, but not all of said planar face in a second geometric pattern that is different from said first geometric pattern; and

an epitaxial layer on the opposite side of said substrate from said planar face and said metal layers.

Claims 12-13 (canceled)

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14. (currently amended) A semiconductor structure according to Claim 13 A semiconductor structure comprising:

a substrate having at least one planar face;

a first metal layer on said planar face, and covering some, but not all of said planar face in a first predetermined geometric pattern;

a second metal layer on said planar face, and covering some, but not all of said planar face in a second geometric pattern that is different from said first geometric pattern; and

an epitaxial layer on the opposite side of said substrate from said planar face and said metal layers;

wherein said substrate and said epitaxial layer comprise a semiconductor device.

- 15. (original) A semiconductor structure according to Claim 14 wherein said device is selected from the group consisting of junction diodes, bipolar transistors, thyristors, MESFETS, JFETS, MOSFETs and photodetectors.
- 16. (currently amended) A semiconductor structure according to Claim 14 A semiconductor structure comprising:

a substrate having at least one planar face;

a first metal layer on said planar face, and covering some, but not all of said planar face in a first predetermined geometric pattern;

a second metal layer on said planar face, and covering some, but not all of said planar face in a second geometric pattern that is different from said first geometric pattern; and

an epitaxial layer on the opposite side of said substrate from said planar face and said metal layers;

wherein said substrate and said epitaxial layer comprise a semiconductor device; and wherein said metal layers form an ohmic contact to said device.

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Page 5

17. (original) A semiconductor structure according to Claim 16 wherein said substrate and said epitaxial layer are silicon carbide and said metal layers are selected from the group consisting of nickel, titanium, gold, alloys thereof, and layered combinations thereof.

18. (canceled)

19. (original) A semiconductor device according to Claim 14 wherein said device comprises a light emitting diode or laser diode that includes a p-n junction, and with said ohmic contact comprising a layer of nickel on said substrate and a layer selected from the group consisting of titanium-gold alloys and titanium-platinum-gold alloys on said nickel layer.

20. (currently amended) A semiconductor wafer comprising:

a silicon carbide substrate and at least one silicon carbide epitaxial layer;

respective primary and secondary orthogonal flats;

respective front and back planar faces;

a plurality of devices on said wafer;

each said device having a first metal layer on said planar face, and covering some, but not all of said planar face in a first predetermined geometric pattern;

and

each said device having a second metal layer on said planar face, and covering some, but not all of said planar face in a second geometric pattern that is different from said first geometric pattern.

Claims 21-26 (canceled)

Ser. No. 10/045,766

Filed: 10/23/2001

Page 6

27. (currently amended) A semiconductor wafer according to Claim 20 wherein: said wafer comprises a silicon carbide substrate and at least one silicon carbide

said warer-comprises a sincon carbide substrate and at least one sincon carbide

epitaxial layer;

said devices comprise light emitting diodes or laser diodes that include a p-n junction;

and

said metal layers comprise a layer of nickel on said substrate and a layer of a titanium-

gold alloy on said nickel layer that form respective ohmic contacts to said devices.

28. (Withdrawn) A quality control method for manufacturing a semiconductor device

comprising:

placing a first metal layer on a semiconductor face of a device in a first predetermined

pattern; and

placing a second metal layer on the same face of the device as the first layer and in a

second predetermined geometric pattern that is different from the first pattern.

29. (Withdrawn) A semiconductor manufacturing method according to Claim 28 and

further comprising:

inspecting the device to identify the presence or absence of one or both of the patterns

on the face.

30. (Withdrawn) A quality control manufacturing method according to Claim 29 and

further comprising discarding the device when one or both of the predetermined patterns are

absent.

31. (Withdrawn) A quality control manufacturing method according to Claim 29

wherein the step of inspecting the face of the device comprises illuminating the metallized

face and scanning the metallized face with a machine inspection system.

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Page 7

- 32. (Withdrawn) A quality control method according to Claim 29 wherein the step of inspecting the device comprises inspecting a transparent device by illuminating the face opposite from the metal layers and scanning the opposite face with a machine inspection system.
- 33. (Withdrawn) A quality control method according to Claim 29 wherein: the step of placing the metal layers comprises placing a pattern with rotational symmetry of C_n, where n is at least 2; and

the step of inspecting each device comprises inspecting either face of the device to identify the presence or absence of the C_n pattern.

34. (Withdrawn) A quality control method for manufacturing wafers with a plurality of semiconductor devices thereon, the method comprising:

placing a first metal layer in a first predetermined geometric pattern on a semiconductor face of each device; and

placing a second metal layer on the same face of each device as said first layer and in a second predetermined geometric pattern that is different from said first geometric pattern;

inspecting the face of each device to identify the presence or absence of one or both of the patterns on each device; and

discarding the devices for which one or both of the patterns are absent.

- 35. (Withdrawn) A quality control method according to Claim 8 wherein the step of inspecting the face of each device comprises evaluating each device with a machine inspection system.
- 36. (Withdrawn) A quality control method according to Claim 34 wherein: the step of placing the metal layers comprises placing a pattern with rotational symmetry of C_n, where n is at least 2; and

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Filed: 10/23/2001

Page 8

the step of inspecting each device comprises inspecting either face of the device to identify the presence or absence of the C_n pattern.

- 37. (Withdrawn) A quality control method according to Claim 34 comprising forming the semiconductor devices on the wafer prior to the step of placing the first metal layer on the devices.
- 38. (Withdrawn) A quality control method according to Claim 37 wherein the step of forming the semiconductor devices comprises forming at least one epitaxial layer on a substrate wafer.
- 39. (Withdrawn) A quality control method according to Claim 38 comprising forming an epitaxial layer of silicon carbide on a silicon carbide substrate.
- 40. (Withdrawn) A quality control method according to Claim 39 comprising placing the metal layers on the face of the substrate opposite the epitaxial layer.
 - 41. (Withdrawn) A quality control method according to Claim 34 comprising: placing the metal layers on a wafer that includes at least one flat; and aligning the metal layers with the flat in a predetermined relationship.
- 42. (Withdrawn) A quality control method according to Claim 41 wherein the step of inspecting the devices comprises aligning the flat of the wafer with a machine inspection system and thereafter evaluating each device with the machine inspection system.
- 43. (Withdrawn) A quality control method according to Claim 35 wherein the step of inspecting the devices comprises inspecting a transparent device by illuminating the face of

Ser. No. 10/045,766

Filed: 10/23/2001

Page 9

the wafer opposite from the metal layers and scanning the illuminated face with a machine inspection system.

Ser. No. 10/045,766

Filed: 10/23/2001

Page 10

Remarks

Applicants again wish to express their appreciation for the Examiner's careful study of the pending application and claims. Further, Applicants wish to confirm that the Amendment document filed on April 15, 2004, is a *bona fide* attempt to advance the prosecution in this case.

In the aforementioned Amendment document, a complete listing of all the claims was not present, specifically; the text for withdrawn Claims 28-43 was omitted. These corrections are made as of May 5, 2004.

Based on the foregoing corrections and claim Amendments previously filed on April 15, 2004, Applicants respectfully submit that Claims 1, 4, 5, 10, 11, 14-17, 19, 20, and 27 are in condition for immediate allowance and the same is respectfully requested.

Respectfully submitted,

James M. Corbitt Reg. No. 52,768

021176 SUMMA & ALLAN, P.A. 11610 North Community House Road Suite 200, Ballantyne Corporate Park Charlotte, NC 28277

Phone: 704-945-6700 Fax: 704-945-6735

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Ser. No. 10/045,766

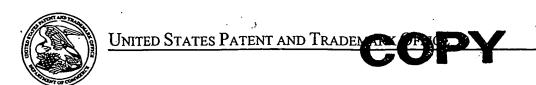
Filed: 10/23/2001

Page 11

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is sent by facsimile to the United States Patent and Trademark Office, c/o Technology Center 2800, Art Unit 2812, Attn: Examiner Andre C. Stevenson, at facsimile number 703-872-9318 on May 5, 2004.

Patricia P. Summers



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NOTICE OF ALLOWANCE AND FEE(S) DUE

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08/25/2004

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ART UNIT PAPER NUMBER

2812

DATE MAILED: 08/25/2004

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR		ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/045,766	10/23/2001	Ralp	h C. Tuttle	5000.142	3061
TITLE OF INVENTION: P.	ATTERN FOR IMPROVE	D VISUAL INSPECTION OF	SEMICONDUCTOR DEVICES	Docket C.B. StaRpt	並る
APPLN. TYPE	SMALL ENTITY	ISSUE FEE	PUBLICATION FEE	TOTAL FEE(S) DUE	DATE DUE
nonprovisional	NO	\$1330	\$300	\$1630	11,06,0004

THE APPLICATION IDENTIFIED ABOVE HAS BEEN EXAMINED AND IS ALLOWED FOR ISSUANCE AS A PATENT. PROSECUTION ON THE MERITS IS CLOSED. THIS NOTICE OF ALLOWANCE IS NOT A GRANT OF PATENT RIGHTS. THIS APPLICATION IS SUBJECT TO WITHDRAWAL FROM ISSUE AT THE INITIATIVE OF THE OFFICE OR UPON PFTITION BY THE APPLICANT. SEE 37 CFR 1.313 AND MPEP 1308.

1... ISSUE FEE AND PUBLICATION FEE (IF REQUIRED) MUST BE PAID WITHIN THREE MONTHS FROM THE MAILING DATE OF THIS NOTICE OR THIS APPLICATION SHALL BE REGARDED AS ABANDONED. THIS STATUTORY PERIOD CANNOT BE EXTENDED. SEE 35 U.S.C. 151. THE ISSUE FEE DUE INDICATED ABOVE REFLECTS A CREDIT FOR ANY PREVIOUSLY PAID ISSUE FEE APPLIED IN THIS APPLICATION. THE PTOL-85B (OR AN EQUIVALENT) MUST BE RETURNED WITHIN THIS PERIOD EVEN IF NO FEE IS DUE OR THE APPLICATION WILL BE REGARDED AS ABANDONED.

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If the SMALL ENTITY is shown as YES, verify your current SMALL ENTITY status:

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II. PART B - FEE(S) TRANSMITTAL should be completed and returned to the United States Patent and Trademark Office (USPTO) with your ISSUE FEE and PUBLICATION FEE (if required). Even if the fee(s) have already been paid, Part B - Fee(s) Transmittal should be completed and returned. If you are charging the fee(s) to your deposit account, section "4b" of Part-B - Fee(s) Transmittal should be completed and an extra copy of the form should be submitted.

III. All communications regarding this application must give the application number. Please direct all communications prior to issuance to Stop ISSUE FEE unless advised to the contrary.

IMPORTANT REMINDER: Utility patents issuing on applications filed on or after Dec. 12, 1980 may require payment of maintenance fees. It is patentee's responsibility to ensure timely payment of maintenance fees when due.

	Application No.	Applicant(s)
A1 P A11 1 1 1111	10/045,766	TUTTLE ET AL.
Notice of Allowability	Examiner	Art Unit
	Andre' C. Stevenson	2812
<u> </u>	Alidie O. Olevellsull	2012
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance and Issue	(OR REMAINS) CLOSED in this ap	plication. If not included
1. This communication is responsive to May 05, 2004.		
2. The allowed claim(s) is/are 1.4.5.11,14-17,19 and 20.		
3. The drawings filed on October 23, 2001 are acceptable.	•	
4. Acknowledgment is made of a daim for foreign priority und	der 35 U.S.C. ≬ 119(a)-(d).	
a) ☐ All b) ☐ Some* c) ☐ None of the CERTIF	- , , , ,	s have been
1. Treceived.		
2. Treceived in Application No. (Series Code / Se	rial Number)	· <u>.</u>
3. received in this national stage application from	n the International Bureau (PCT Rul	e 17.2(a)).
* Certified copies not received:	·	
5. Acknowledgement is made of a claim for domestic priority	under 35 U.S.C. & 119(e).	
A SHORTENED STATUTORY PERIOD FOR REPLY to comply to THREE MONTHS FROM THE "DATE MAILED" of this Office Act ABANDONMENT of this application. Extensions of time may be	tion. Failure to timely comply will res available under the provisions of 37	cult in CFR 1.136(a).
 Note the attached EXAMINER'S AMENDMENT or NOTIC the oath or declaration is deficient. A SUBSTITUTE OAT 	E OF INFORMAL APPLICATION (FITH OR DECLARATION IS REQUIRED.)	PTO-152) which gives reason(s) why ED.
Applicant MUST submit NEW FORMAL DRAWINGS		
(a) ☐ because the originally filed drawings were declared b	y applicant to be informal.	_
(b) including changes required by the Notice of Draftsper	rson's Patent Drawing Review(PTO	-948) attached
1) ☐ hereto or 2) ☐ to Paper No		
(c) ☐ including changes required by the proposed drawing	correction filed, which has b	peen approved by the examiner.
(d) ☐ including changes required by the attached Examine	r's Amendment / Comment.	
Identifying indicia such as the application number (see 3 drawings. The drawings should be filed as a separate population. Draftsperson.	37 CFR 1.84(c)) should be written aper with a transmittal letter addr	on the reverse side of the essed to the Official
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Attachment(s)		•
1⊠ Notice of References Cited (PTO-892)		nal Patent Application (PTO-152)
3 Notice of Draftperson's Patent Drawing Review (PTO-948)		nary (PTO-413), Paper No
5☐ Information Disclosure Statements (PTO-1449), Paper No. 2 7☐ Examiner's Comment Regarding Requirement for Deposit		endment/Comment tement of Reasons for Allowance
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		Notice of References)———s Cited		Application/Control 10/045,766 Examiner Andre' C. Stevens	son	Applicant(s)/Pa Reexamination TUTTLE ET Al Art Unit 2812	1
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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(0/13/04 Soos, 14Z Claims 10 and 27 are not mentioned in the Votre of Albourance. Telephone Conversation with Edaminer Stevenson: The PTO computer System was unavailable when & called, but he will investigate the matter on 10/14/04 and call me of there is a reason why these claims were omitted. Otherwise, he will issue a supplemental Allowance this Week.



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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/045,766	10/23/2001	Ralph C. Tuttle	5000.142	3061
21176 7	590 10/19/2004		EXAM	INER
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CHARLOTTE	, NC 28277	RECEIVED	2812	
•		OCT 27 2004	DATE MAILED: 10/19/200	4
•		& ALLAN, P.A.		
	·		Docket C.B StaRpt	= 1

Please find below and/or attached an Office communication concerning this application or proceeding.

Notice of Allowability Exam	e' C. Stevenson	TUTTLE ET AL. Art Unit 2812	å
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	EMAINS) CLOSED in to the or other appropriate of	the correspondence addre- his application. If not included communication will be mailed	ss d in due course
This communication is responsive to <u>May 05, 2004</u> .			
The allowed claim(s) is/are <u>1,4,5,10,11,14-17,19,20 and 27</u> .			
The drawings filed on October 23, 2001 are acceptable.	1100 5 440(a) (d)		
Acknowledgment is made of a claim for foreign priority under 35	U.S.C. § 119(a)-(a).	uments have been	
a) ☐ All b) ☐ Some* c) ☐ None of the CERTIFIED c	oples of the priority doc	untents have been	
1. received.			
received in Application No. (Series Code / Serial No.	umber)		
3. received in this national stage application from the	International Bureau (Po	CT Rule 17.2(a)).	
* Certified copies not received:			
Acknowledgement is made of a claim for domestic priority under	· 35 U.S.C. & 119(e).	•	
SHORTENED STATUTORY PERIOD FOR REPLY to comply with the IREE MONTHS FROM THE "DATE MAILED" of this Office Action. IT BANDONMENT of this application. Extensions of time may be available.			
Note the attached EXAMINER'S AMENDMENT or NOTICE OF the oath or declaration is deficient. A SUBSTITUTE OATH OF	INFORMAL APPLICAT	ION (PTO-152) which gives	reason(s) why
Applicant MUST submit NEW FORMAL DRAWINGS (a) because the originally filed drawings were declared by app	olicant to be informal.		
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4) U harata or 2) U to Paper No			
(c) including changes required by the proposed drawing corre	ection filed, which	th has been approved by the	examiner.
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Identifying indicia such as the application number (see 37 CI drawings. The drawings should be filed as a separate paper Draftsperson.	FR 1.84(c)) should be very with a transmittal letter	written on the reverse side or ar addressed to the Official	of the
B. ☐ Note the attached Examiner's comment regarding REQUIREN	MENT FOR THE DEPOS	SIT OF BIOLOGICAL MATER	IAL.
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Attachment(s)			
Notice of References Cited (PTO-892)	2 Notice	of Informal Patent Application	ı (PTO-152)
Notice of Draftperson's Patent Drawing Review (PTO-948)	4☐ Intervie	w Summary (PTO-413), Pape	er No
5 Information Disclosure Statements (PTO-1449), Paper No. 2.	6 <u> </u>	ner's Amendment/Comment	or Allowanaa
☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	8⊠ Examir 9⊡ Other	ner's Statement of Reasons fo	n Allowance

Application/Control Number: 10/045,766

Art Unit: 2812

Allowable Subject Matter

Claims #1, 4, 5, 10, 11, 14 through 17, 19, 20 and 27 are allowed.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866 – 217 – 9197 (toll-free).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Andre C. Stevenson whose telephone number is (571) 272 1683. The examiner can normally be reached on Monday through Friday from 8:00 am to 5:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Niebling, can be reached on (571) 272 1683. The fax phone number for the organization where this application or proceeding is assigned is (703) 308 7724.

Application/Control Number: 10/045,766

Art Unit: 2812

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308 1782. Also, the proceeding number can be used to fax information;

• (703) 872-9306

Andre C. Stevenson

Art Unit 2812

10/14/04

John F. Niebling

Supervisory Patent Examiner Technology Center 2800 complete and send this form, together wit

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•			or E	ax (703) 746-4000		
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		·	-	Novemb	er 23, 2004	(Date)
APPLICATION NO.	FILING DATE	I	TRST NAMEL	INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/045,766	10/23/2001		Ralph C	. Tuttle	5000.142	3061
	ATTERN FOR IMPROVED	VISUAL INSPEC	TION OF SE	EMICONDUCTOR DEVICES	· ·	
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Inventors: Tuttle et al.

Serial No. 10/045,766

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